

FIG. 1

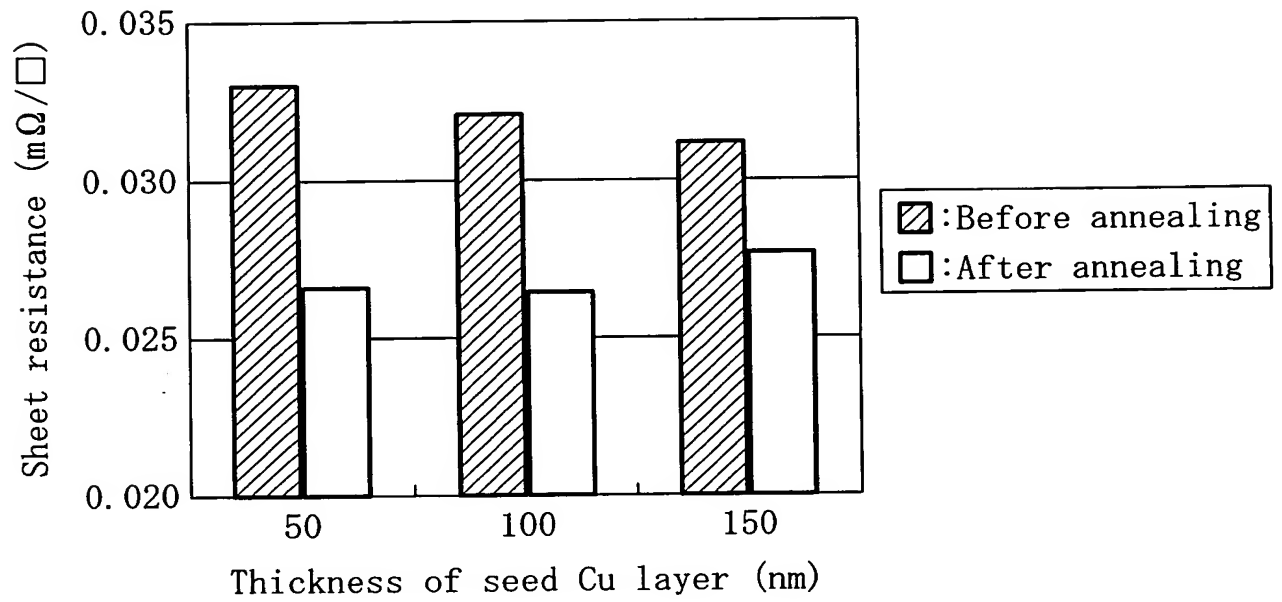


FIG. 2

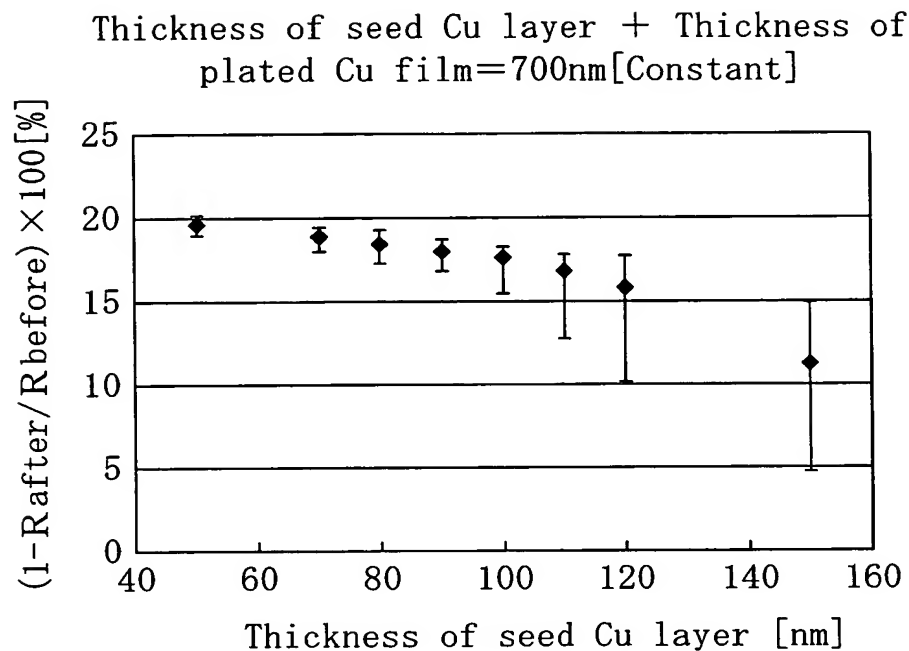
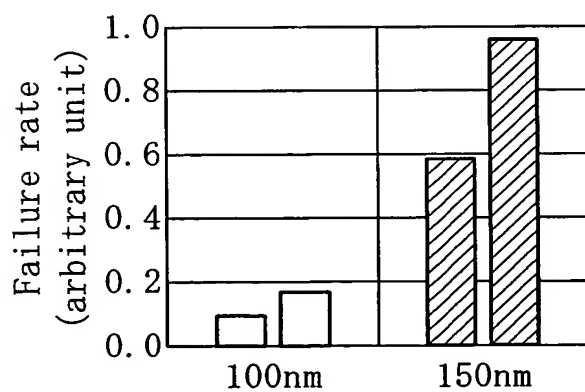


FIG. 3



Thickness of seed layer

Results of high temperature storage test (250°C) for via resistance

FIG. 4A

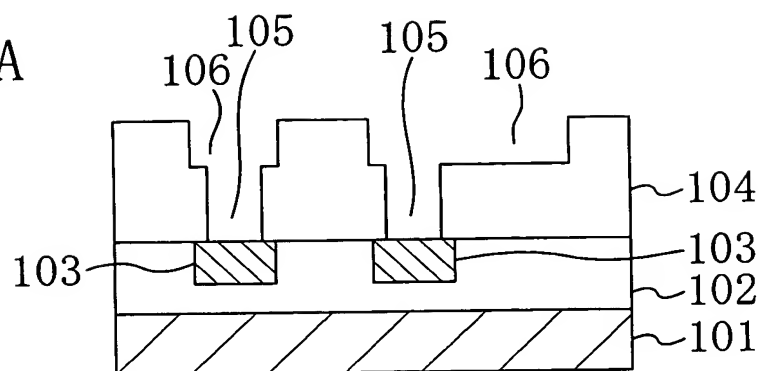


FIG. 4B

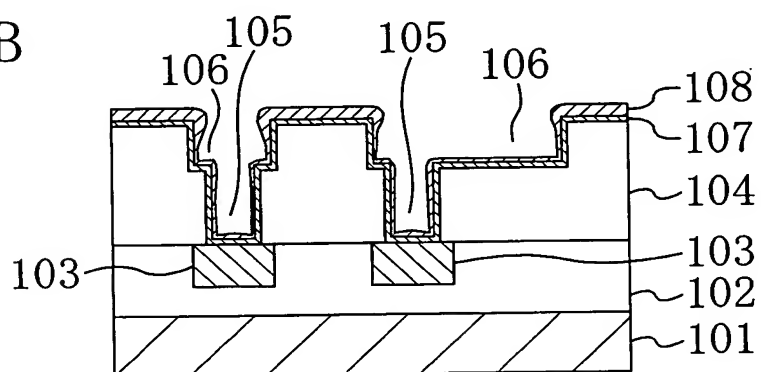


FIG. 4C

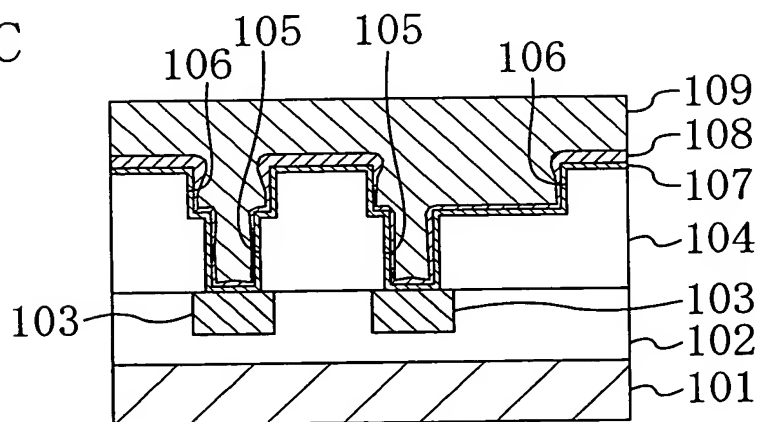


FIG. 5A

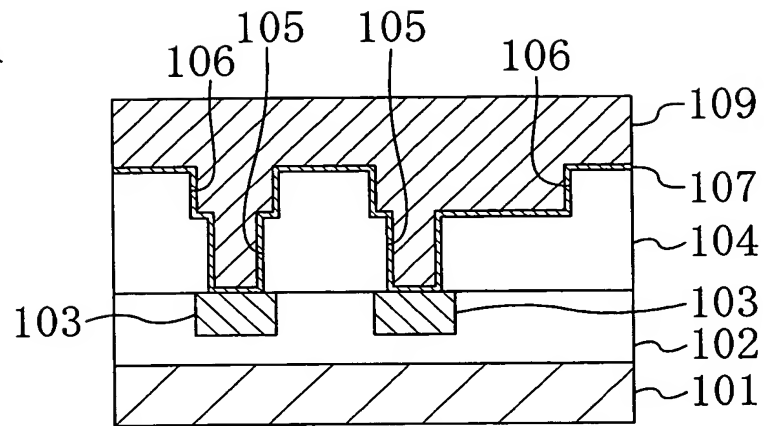


FIG. 5B

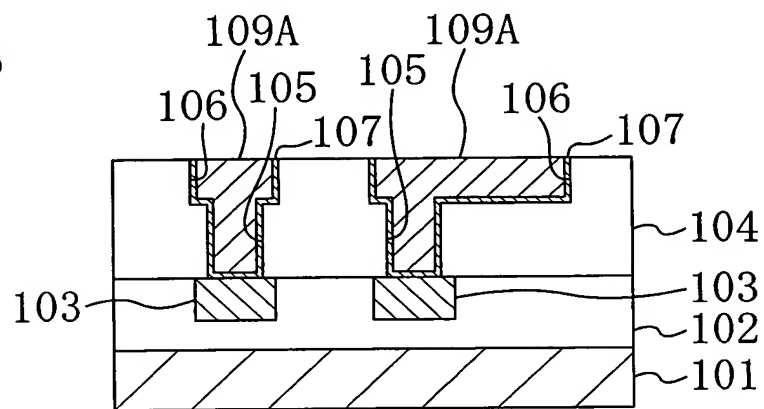


FIG. 5C

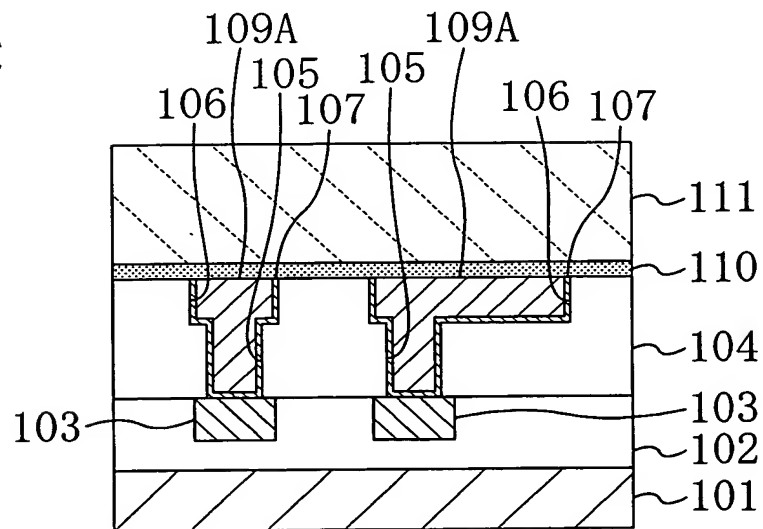


FIG. 6A

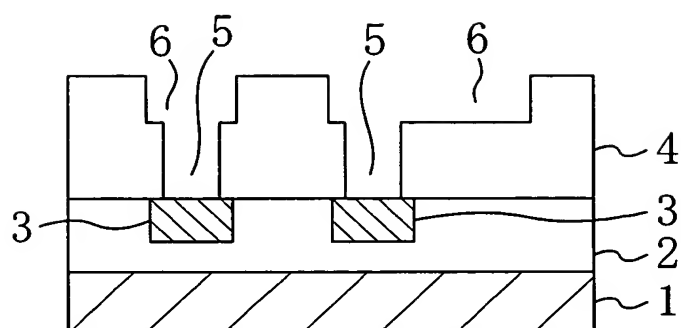


FIG. 6B

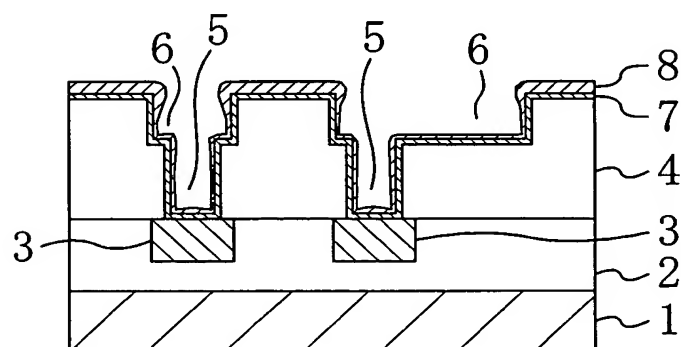


FIG. 6C

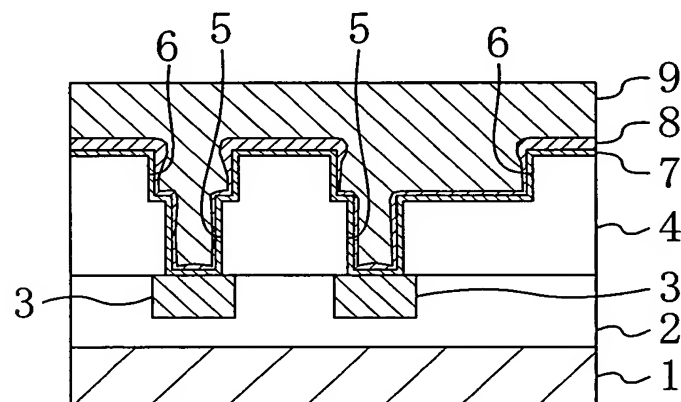


FIG. 6D

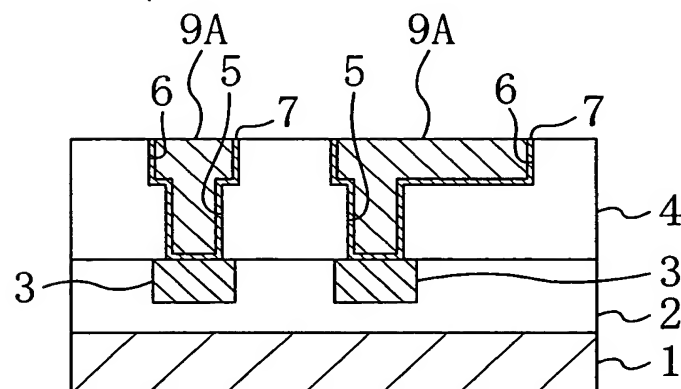


FIG. 7
PRIOR ART

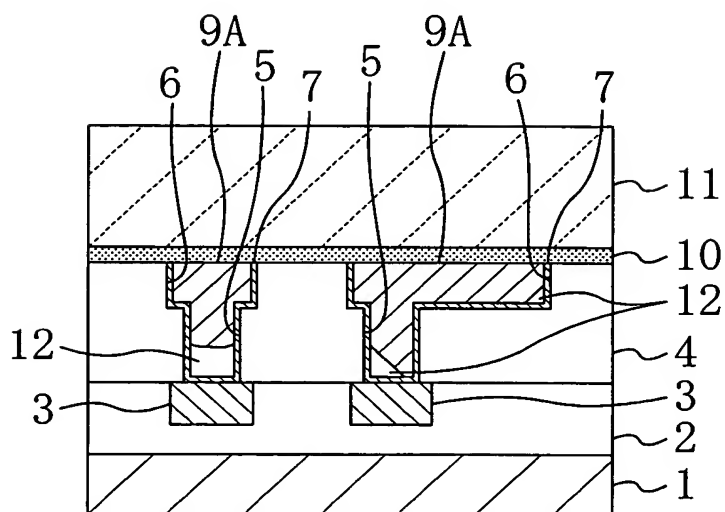


FIG. 8
PRIOR ART

